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Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number. Substitute for form 1449A/PTO Complete if Known **Application Number** Unknown INFORMATION DISCLOSURE **Filing Date** Herewith STATEMENT BY APPLICANT First Named Inventor Mark A. Lemkin Group Art Unit Unknown (use as many sheets as necessary) Examiner Name Unknown Sheet 1 of Attorney Docket Number AIMI-01833US0

		T		U.S. PATENT DOCI	JMENTS	
Examiner Initials*	Cite No.1	U.S. Patent Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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STA	TEMENT	RY	APPLICANT	First Named Inventor	Mark A. Lemkin		
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Sheet	2	of	5	Attorney Docket Number	AIMI-01833US0		

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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INFO	RMATION	l DIS	SCLOSURE	Filing Date	Herewith Mark A. Lemin		
STA	TEMENT E	3Y A	APPLICANT	First Named Inventor			
317				Group Art Unit	Unknown		
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Sheet	3	of	5	Attorney Docket Number	AIMI-01833US0		

				U.S. PATENT DOC	JMENTS		
Examiner	Cite		U.S. Patent	Document Kind Code <sup>2</sup>	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant
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	Cite No. <sup>1</sup>	Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> ( <i>if known</i> )	Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear	T <sub>6</sub>
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				Application Number	Unknown	
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CT/	TEMENI	T RV	APPLICANT	First Named Inventor	Mark A. Lemin	
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Sheet	4	of	5	Attorney Docket Number	AIMI-01833US0	

		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	—
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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Substitute fo	or form 1449A/F	то		Complete if Known			
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				U.S. PATENT DOCU	JMENTS	
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